

**SK8603160L**

**Silicon N-channel MOS FET**

For Load-switching / For DC-DC Converter

■ Features

- Low Drain-source On-state Resistance :  $R_{DS(on)}$  typ = 3.3 mΩ (VGS = 4.5 V)
- Halogen-free / RoHS compliant  
 (EU RoHS / UL-94 V-0 / MSL : Level 1 compliant)

■ Marking Symbol : 16

■ Packaging

Embossed type (Thermo-compression sealing) : 3 000 pcs / reel (standard)

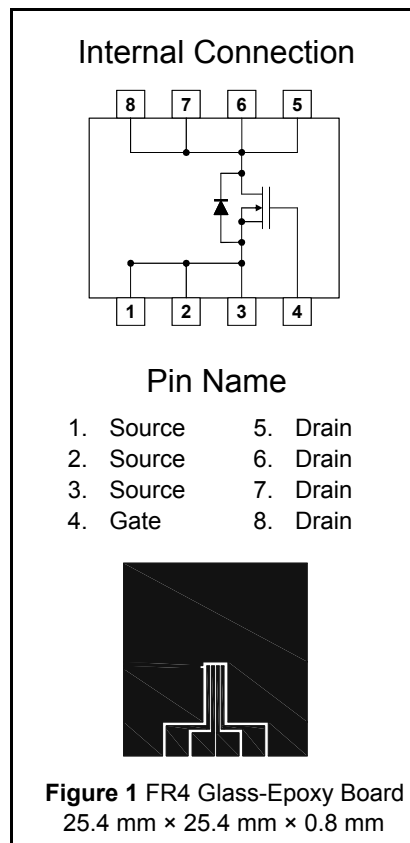
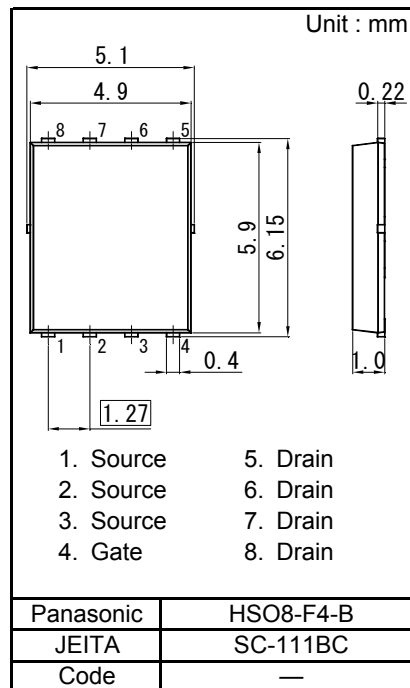
■ Absolute Maximum Ratings  $T_a = 25\text{ }^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain to Source Voltage	VDS	30	V
Gate to Source Voltage	VGS	±20	
Drain Current	ID	$T_a = 25\text{ }^\circ\text{C}, t = 10\text{ s}^{-1}$	34
		$T_a = 25\text{ }^\circ\text{C}, \text{DC}^{*1}$	22
		$T_c = 25\text{ }^\circ\text{C}$	70
		Pulsed, $T_{ch} < 150\text{ }^\circ\text{C}^{*2}$	102
Total Power Dissipation	PD	$T_a = 25\text{ }^\circ\text{C}, \text{DC}^{*1}$	2.8
		$T_c = 25\text{ }^\circ\text{C}$	28
Thermal Resistance	Channel to Ambient	$R_{th(ch-a)}$	44
	Channel to Case	$R_{th(ch-c)}$	4.5
Channel Temperature	$T_{ch}$	150	°C
Operating ambient temperature	$T_{opr}$	-40 to +85	
Storage Temperature Range	$T_{stg}$	-55 to +150	
Avalanche Current (Single pulse) <sup>*3</sup>	IAR	17	A
Avalanche Energy (Single pulse) <sup>*3</sup>	EAR	36	mJ

Note \*1 Device mounted on a glass-epoxy board in Figure 1

\*2 Pulse test: Ensure that the channel temperature does not exceed 150 °C

\*3 VDD = 24 V, VGS = 10 to 0 V, L = 0.1 mH, T<sub>ch</sub> = 25 °C (initial)



■ Electrical Characteristics Ta = 25 °C ± 3 °C

Static Characteristics

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Drain-source Breakdown Voltage	VDSS	ID = 1 mA, VGS = 0 V	30			V
Zero Gate Voltage Drain Current	IDSS	VDS = 30 V, VGS = 0 V			10	μA
Gate-source Leakage Current	IGSS	VGS = ±16 V, VDS = 0 V			±10	μA
Gate-source Threshold Voltage	Vth	ID = 3.35 mA, VDS = 10 V	1.3		3	V
Drain-source On-state Resistance	RDS(on)1	ID = 17 A, VGS = 10 V		2.5	3.3	mΩ
	RDS(on)2	ID = 17 A, VGS = 4.5 V		3.3	4.3	

Dynamic Characteristics

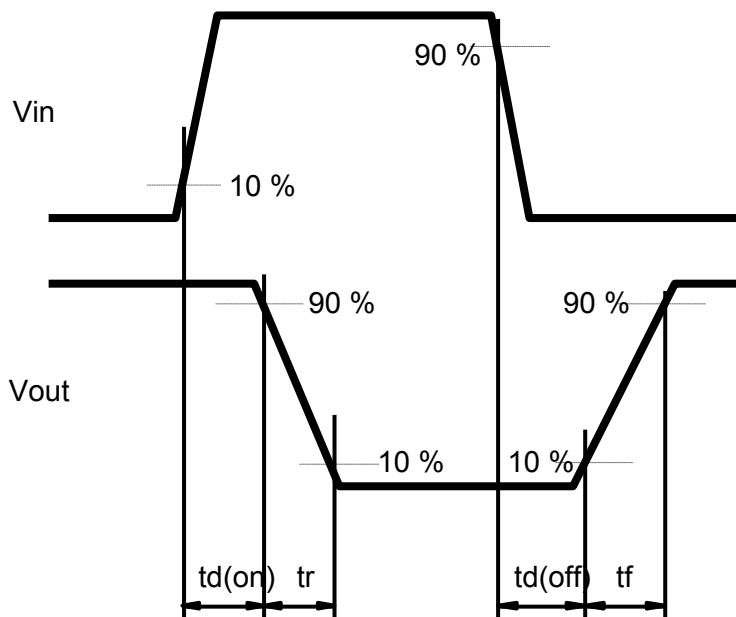
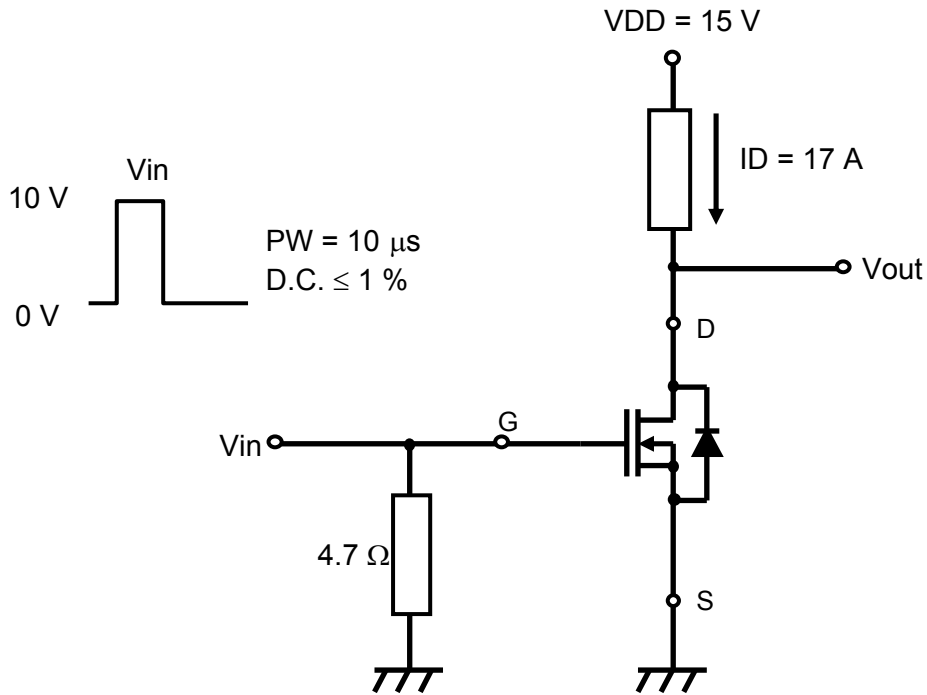
Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Input Capacitance	Ciss	VDS = 10 V, VGS = 0 V f = 1 MHz		2 800	3 920	pF
Output Capacitance	Coss			330	462	
Reverse Transfer Capacitance	Crss			230	368	
Turn-on Delay Time <sup>*1</sup>	td(on)	VDD = 15 V, VGS = 0 to 10 V		13		ns
Rise Time <sup>*1</sup>	tr	ID = 17 A		12		
Turn-off Delay Time <sup>*1</sup>	td(off)	VDD = 15 V, VGS = 10 to 0 V		52		ns
Fall Time <sup>*1</sup>	tf	ID = 17 A		8		
Total Gate Charge	Qg	VDD = 15 V, VGS = 0 to 4.5 V ID = 17 A		22		nC
Gate to Source Charge	Qgs			7		
Gate to Drain Charge	Qgd			9		
Gate resistance	rg	f = 5 MHz		1.2	3	Ω

Body Diode Characteristic

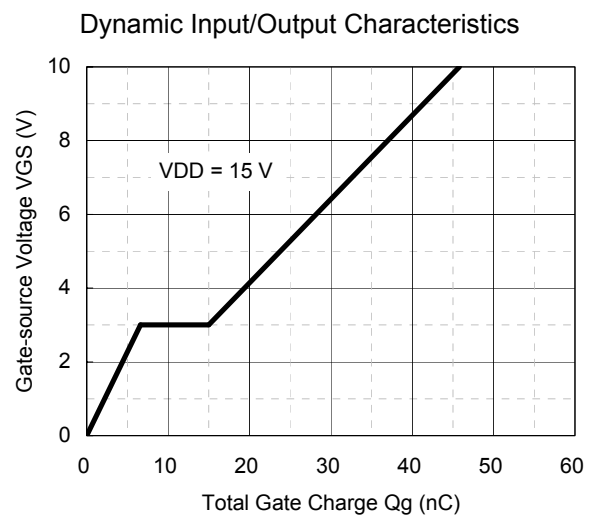
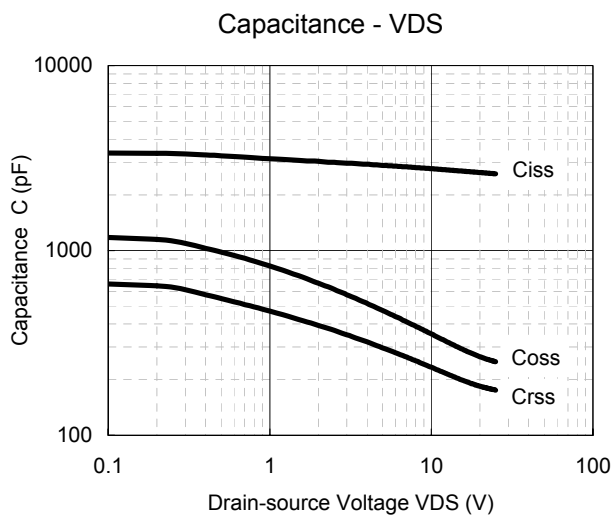
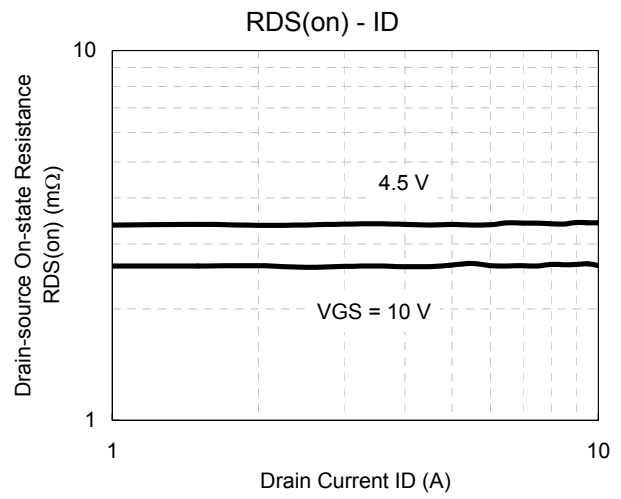
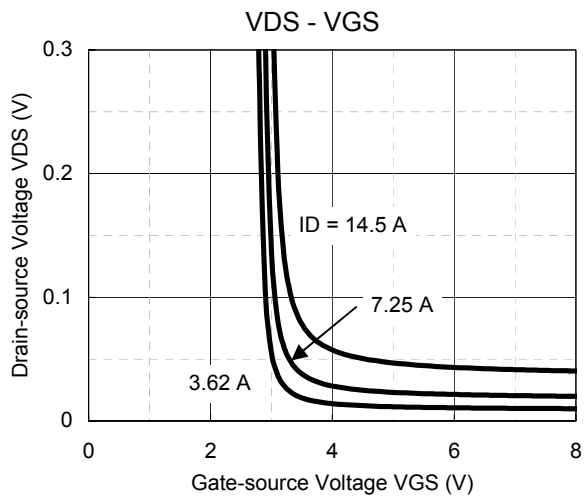
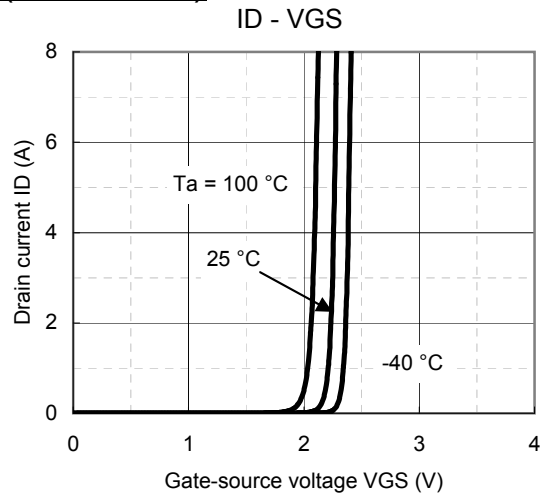
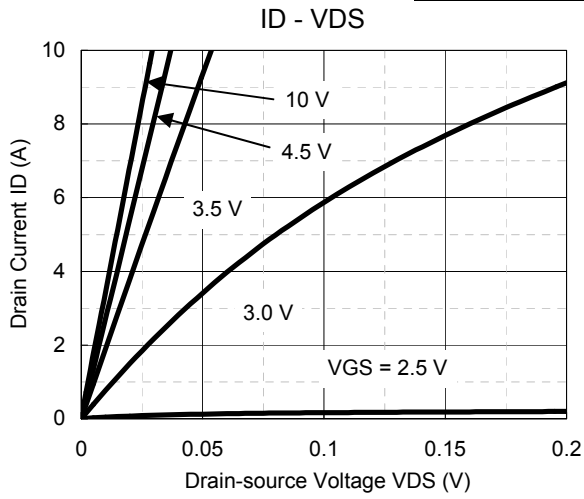
Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Diode Forward Voltage	VSD	IS = 17 A, VGS = 0 V		0.8	1.2	V

Note : 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.  
2. \*1 Measurement circuit for Turn-on Delay Time / Rise Time / Turn-off Delay Time / Fall Time

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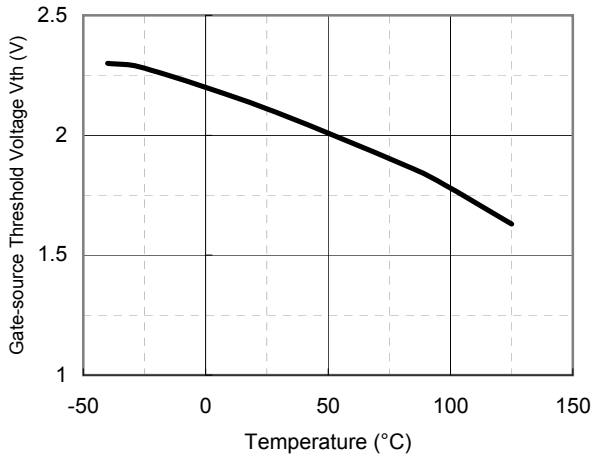


Technical Data ( reference )

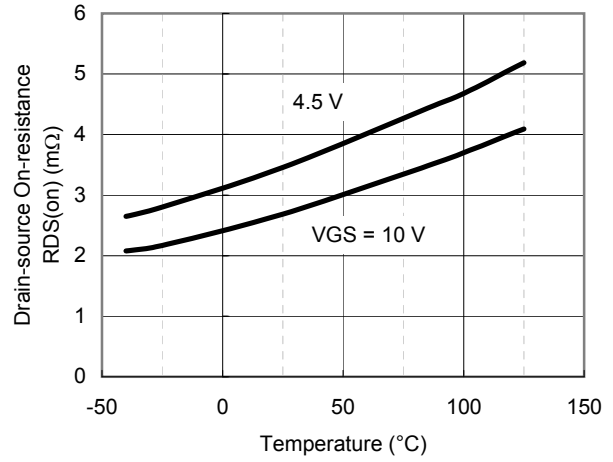


Technical Data ( reference )

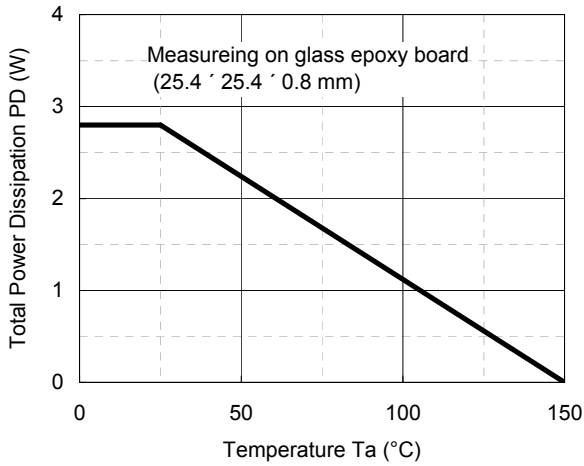
V<sub>th</sub> - T<sub>a</sub>



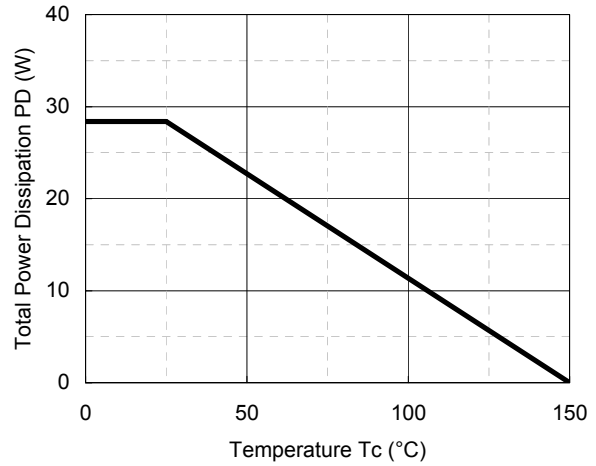
R<sub>DS(on)</sub> - T<sub>a</sub>



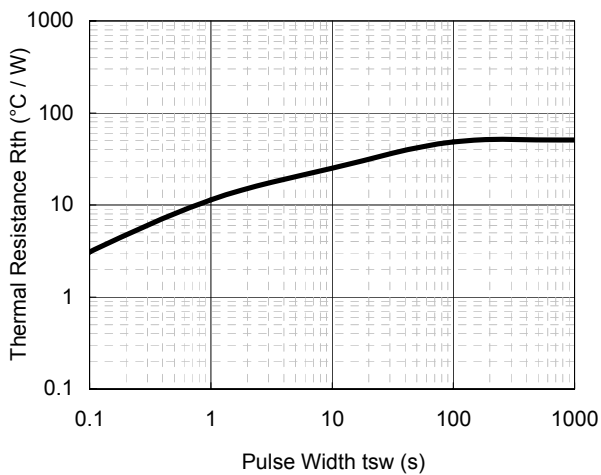
PD - T<sub>a</sub>



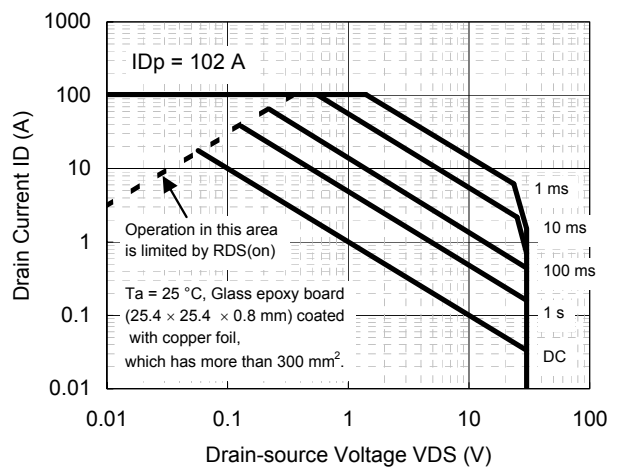
PD - T<sub>c</sub>



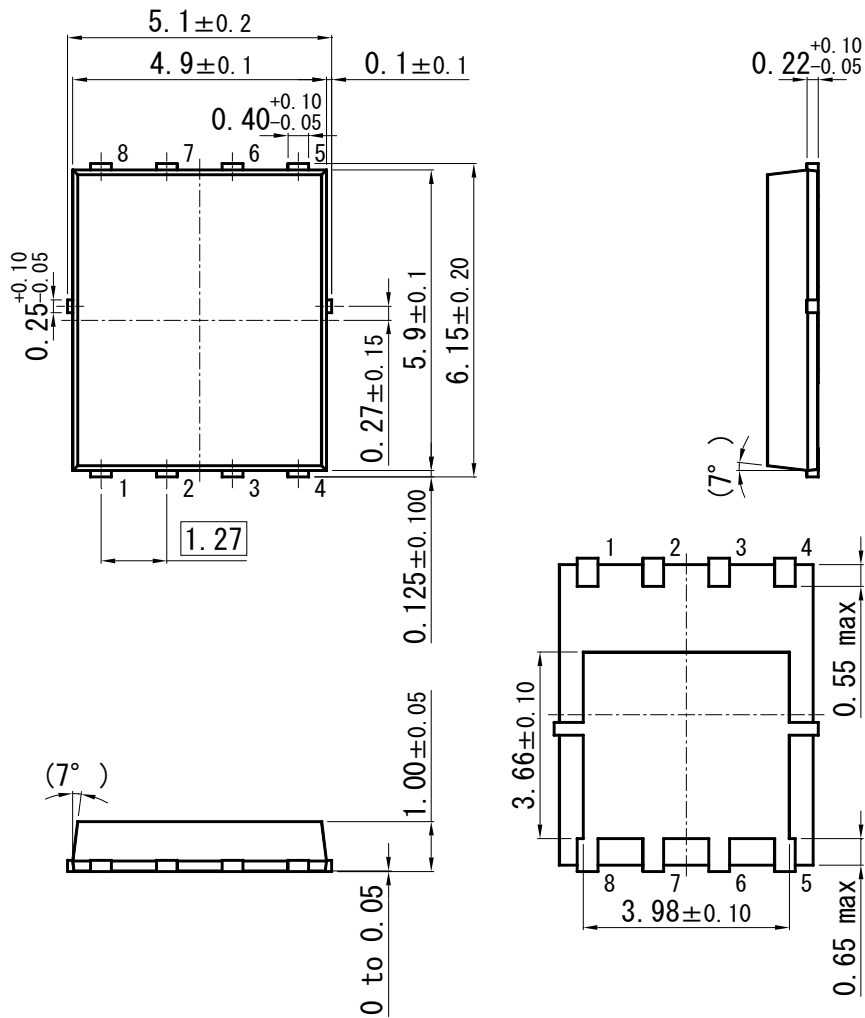
R<sub>th</sub> - t<sub>sw</sub>



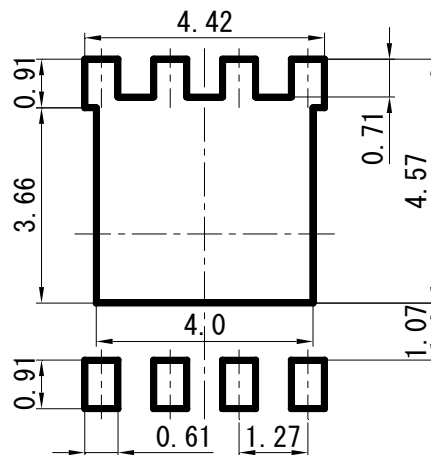
Safe Operating Area



HSO8-F4-B



■ Land Pattern (Reference) (Unit : mm)



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